



**ALPHA & OMEGA**  
SEMICONDUCTOR

# AOT466L/AOB466L

## 60V N-Channel MOSFET

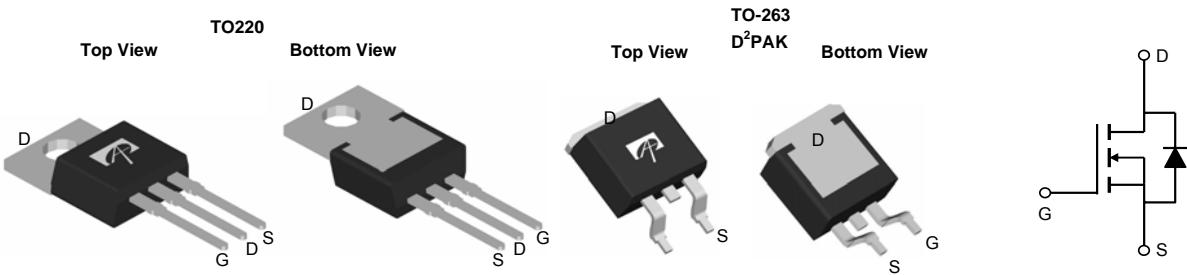
### General Description

The AOT466L & AOB466L combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

### Product Summary

$V_{DS}$	60V
$I_D$ (at $V_{GS}=10V$ )	180A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 3.9mΩ

100% UIS Tested  
100%  $R_g$  Tested



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 25$	V
Continuous Drain Current <sup>G</sup>	$I_D$	180	A
$T_C=100^\circ C$		140	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	540	
Continuous Drain Current	$I_{DSM}$	15	A
$T_A=70^\circ C$		12	
Avalanche Current <sup>C</sup>	$I_{AS}, I_{AR}$	80	A
Avalanche energy $L=0.3mH^C$	$E_{AS}, E_{AR}$	960	mJ
Power Dissipation <sup>B</sup>	$P_D$	333	W
$T_C=100^\circ C$		167	
Power Dissipation <sup>A</sup>	$P_{DSM}$	1.9	W
$T_A=70^\circ C$		1.2	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	12	°C/W
Maximum Junction-to-Ambient <sup>A D</sup>	Steady-State		54	°C/W
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.35	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS} = \pm 25\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	3.6	4.3	5	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	540			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		3.2	3.9	$\text{m}\Omega$
		TO220 $T_J=125^\circ\text{C}$		5.2	6.3	
		$V_{GS}=10\text{V}, I_D=20\text{A}$ TO263		2.9	3.6	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		60		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.67	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				180	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$	4485	5607	6730	pF
$C_{oss}$	Output Capacitance		750	1076	1400	pF
$C_{rss}$	Reverse Transfer Capacitance		280	485	680	pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.35	0.75	1.2	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=20\text{A}$	85	108	130	nC
$Q_{gs}$	Gate Source Charge		24	30	36	nC
$Q_{gd}$	Gate Drain Charge		27	46	65	nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		31		ns
$t_r$	Turn-On Rise Time			29		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			41		ns
$t_f$	Turn-Off Fall Time			13		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$	20	35	50	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$	190	273	355	nC

A. The value of  $R_{\text{DJA}}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{DJA}}$  and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ . Maximum UIS current limited by test equipment.

D. The  $R_{\text{DJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{JJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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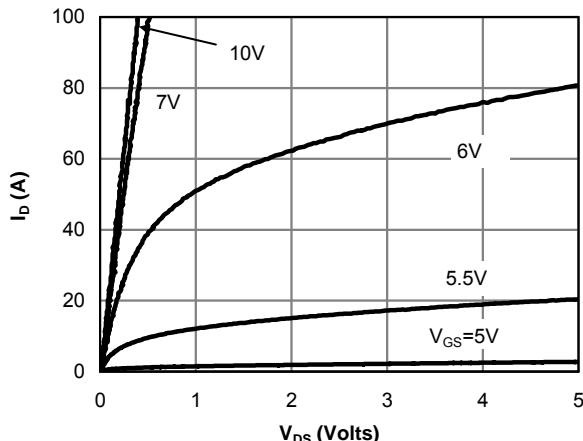
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Fig 1: On-Region Characteristics (Note E)

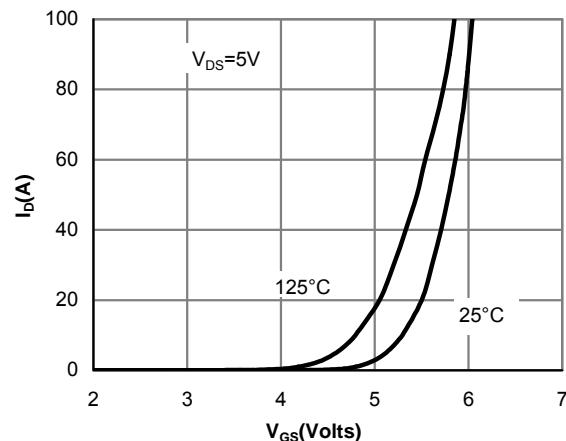


Figure 2: Transfer Characteristics (Note E)

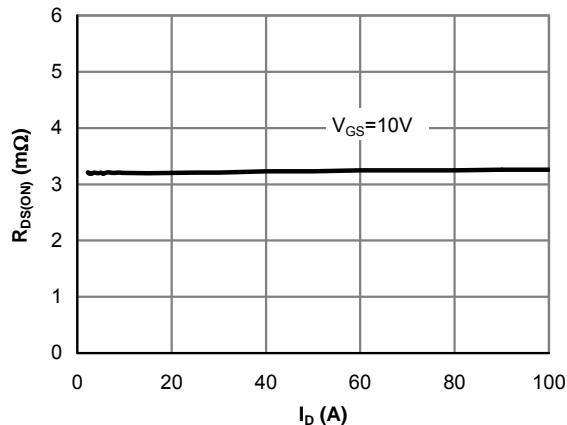


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

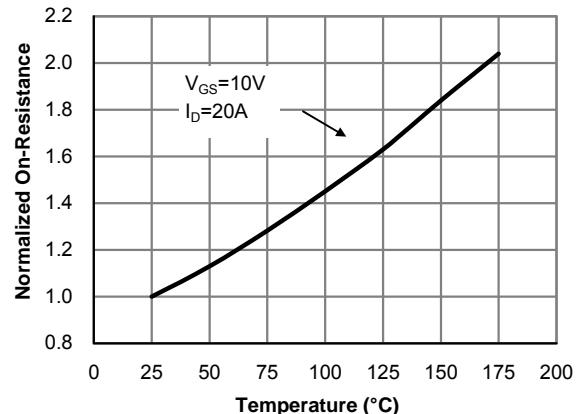


Figure 4: On-Resistance vs. Junction Temperature (Note E)

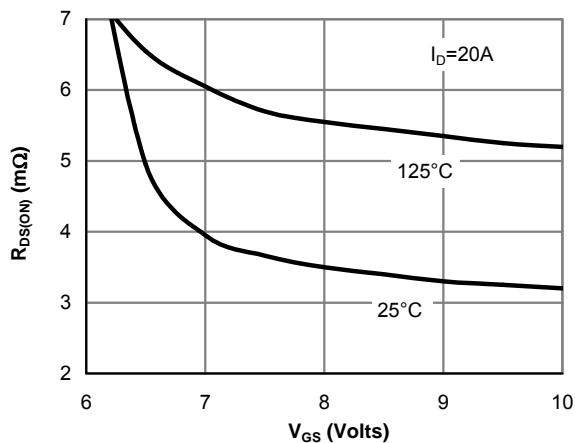


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

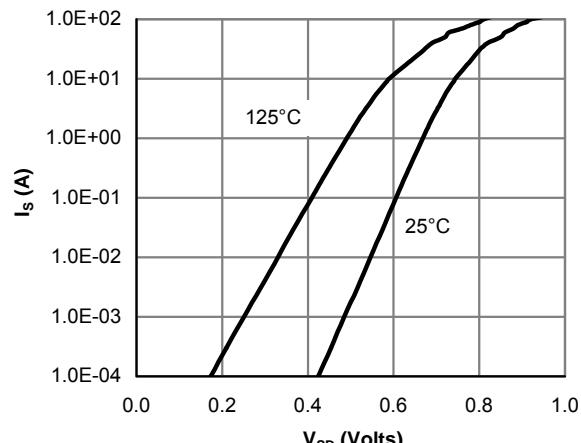


Figure 6: Body-Diode Characteristics (Note E)

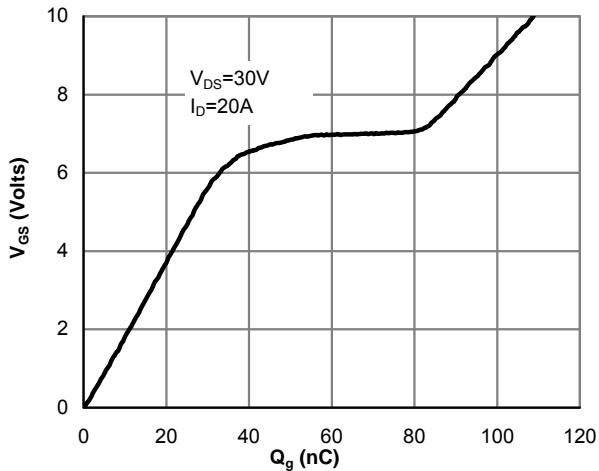
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Figure 7: Gate-Charge Characteristics

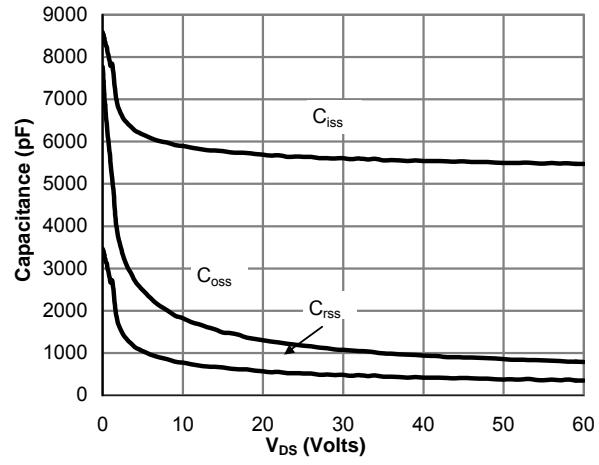


Figure 8: Capacitance Characteristics

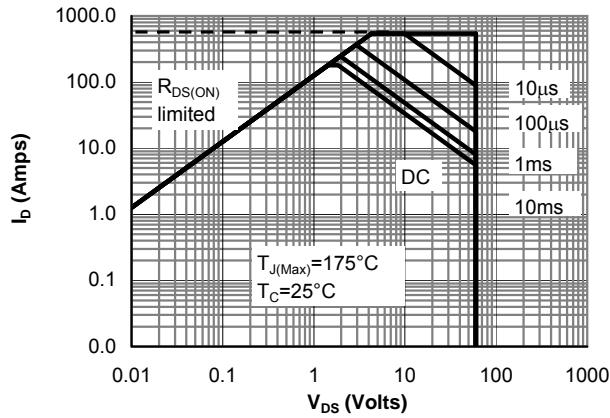


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

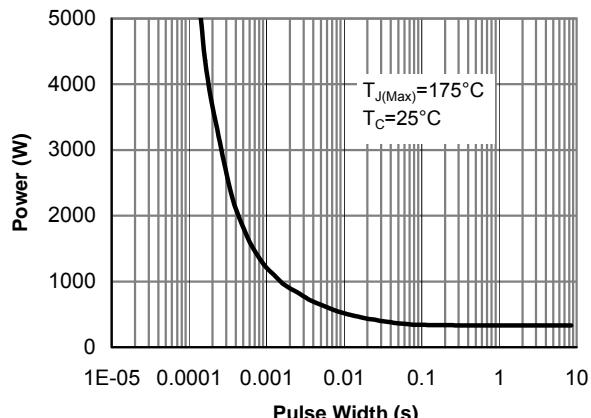


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

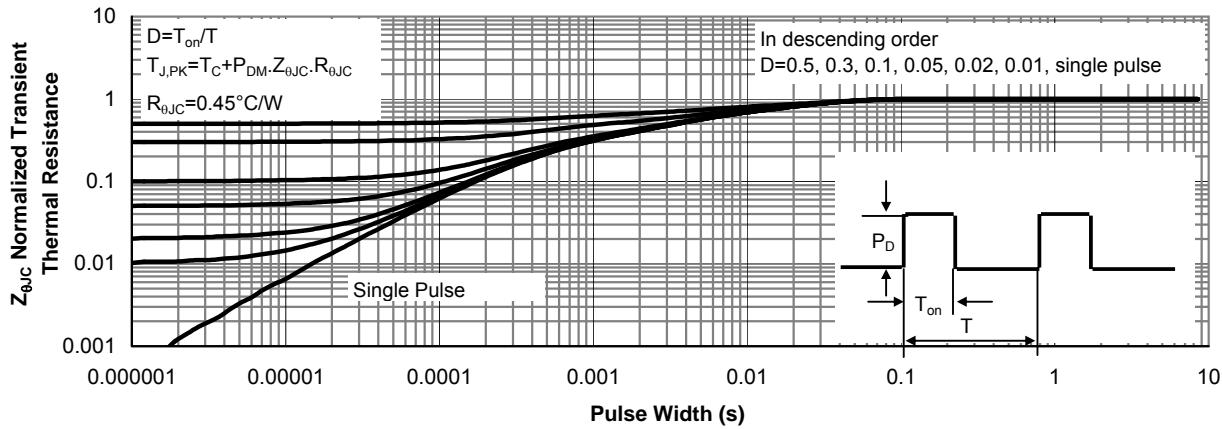
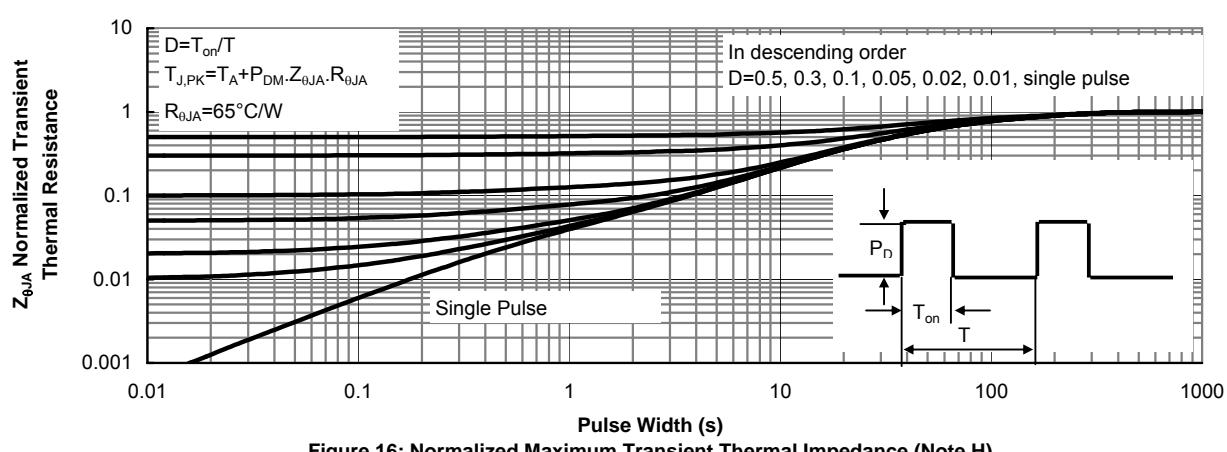
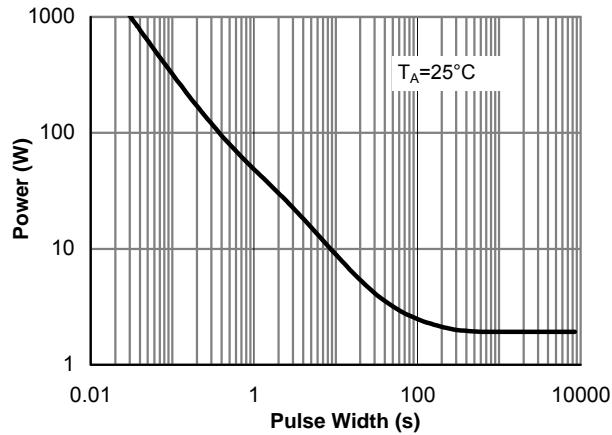
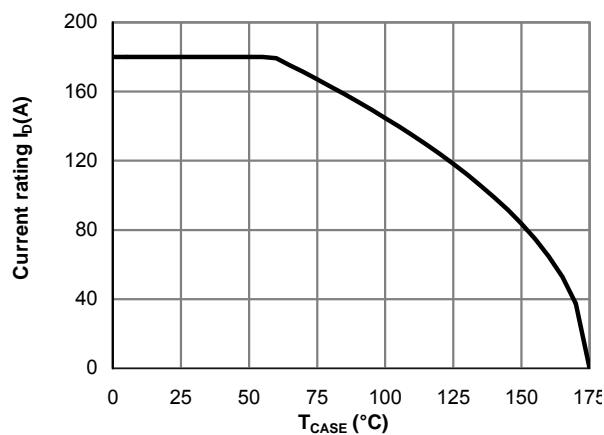
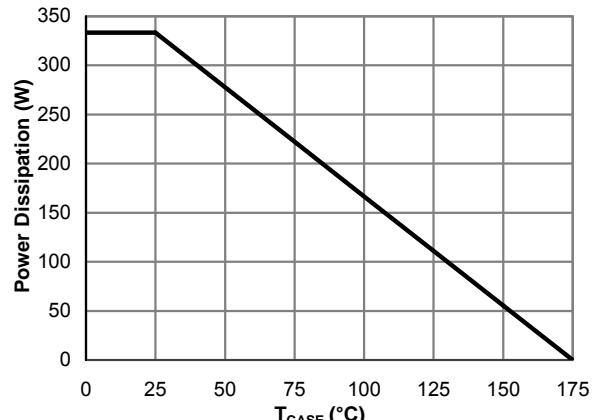
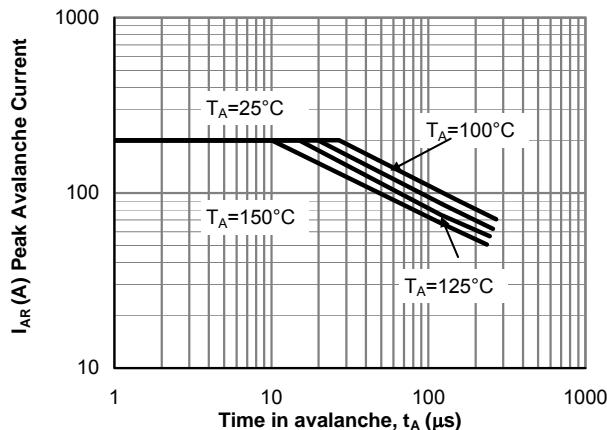
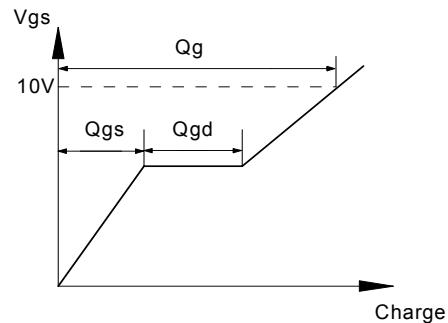
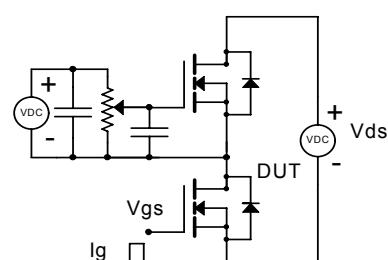


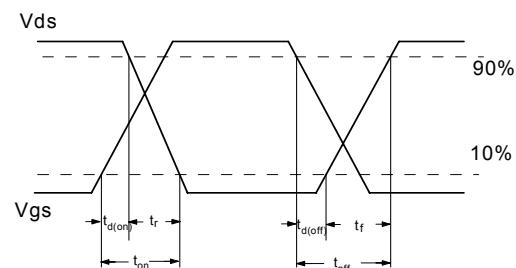
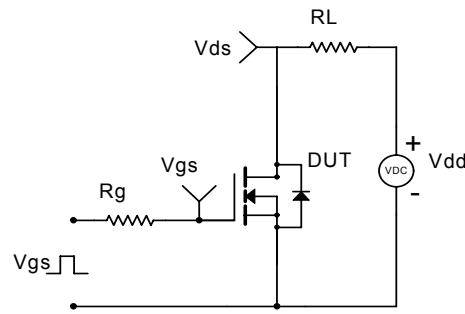
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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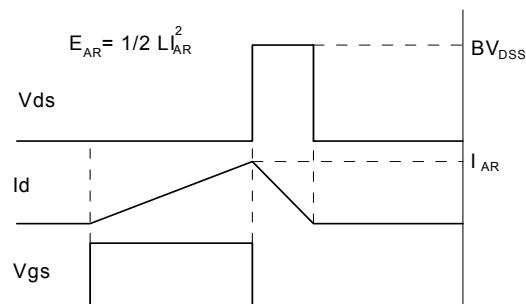
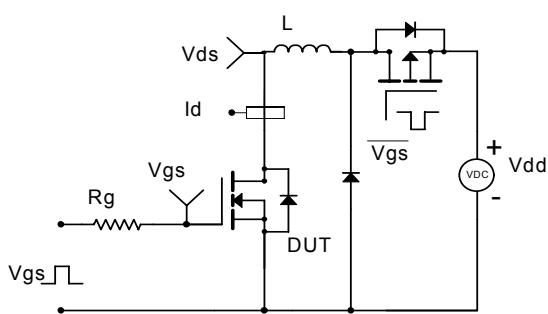
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



### Diode Recovery Test Circuit & Waveforms

